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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Substitute for form 1449A/PTO

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 Complete if Known

 Application Number
 10/603,019

 Filing Date
 June 26, 2003

 First Named Inventor
 Shunpei YAMAZAKI et al.

 An Unit
 2818

 Examiner Name
 Dung-Anh LE

 Attorney Docket Number
 740756-2626

			U.S. PATENT DOC	UMENTS	
Examiner Initials*	Cite No.	U.S. Petent Document Number - Kind Code ((f known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
10		US-5,323,042 -	06-21-1994	MATSUMOTO	-
. 1		US-5,412,493 ,	05-02-1995	KUNII et al.	
	1	US-5,528,056 ·	06-18-1996	SHIMADA et al.	
		US-5,594,569	01-14-1997	KONUMA et al.	
	1	US-5,652,158 /	07-29-1997	BAE	
		US-5,757,444	05-26-1998	TAKEMURA	
		US-5,767,930 /	06-16-1998	KOBAYASHI et al.	
		US-5,852,488 /	12-22-1998	TAKEMURA	
	-	US-5,953,582 C	09-14-1999	YUDASAKA et al.	
		US-6,013,929 /	01-11-2000	OHTANI	
		US-6,088,070 /	07-11-2000	OHTANI et al.	
		US-6,140,162 -	10-31-2000	YEO	-
		US-6,166,436 ·	12-26-2000	MAEDA et al.	+==
1		US-2001/0000627 A1 -	05-03-2001	HAYAKAWA et al.	
		US-6,323,490 B1 (11-27-2001	IKEDA et al.	
		US-6,337,731 B1 ·	01-08-2002	TAKEMURA	
		US-6,399,988 B1 /	06-04-2002	YAMAZAKI	
		US-6,531,713 B1	03-11-2003	YAMAZAKI	
		US-6,579,736 B2 -	06-17-2003	YAMAZAKI	
1		US-6,693,681 B1 ~	02-17-2004	TAKEMURA	
D//2		US-6,734,924 B2 -	05-11-2004	HIRAKATA et al.	
		US-6,777,255 B2 ·	08-17-2004	YAMAZAKI	<u></u>

	,	FC	REIGN PATENT	DOCUMENTS		
Examiner laitials	Cite No. ¹	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant	
0 1		Country Code Number (if known)	MM-DD-YYYY		Figures Appear	1*
Dh		JP 63-222443 -	09-16-1988	OKABE	~~~	Abst
		JP 03-091721	04-17-1991	SAJTO et al.		Abst
		JP 05-307165	11-19-1993	OZAWA		Abst
		JP 07-326767	12-12-1995	IKEDA		Abst
		JP 09-074204	03-18-1997	MOROSAWA		Abst
		JP 10-012895	01-16-1998	KAWAURA et al.		Abst
D		ЛР 11-097701	04-09-1999	INOUE		Abst
		EP 0 989 614 A2	03-29-2000	YAMAZAKI et al.		

Examiner .	Date
Signature	Considered

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Complete if Known Substitute for form 1449B/PTO 10/603,019 Application Number INFORMATION DISCLOSURE Filing Date June 26, 2003 **STATEMENT BY APPLICANT** Shunpei YAMAZAKI et al. First Named Inventor (use as many sheets as necessary) 2818 Group Art Unit Dung-Anh LE Examiner Name 2 Attorney Docket Number 740756-2626

		OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
De		U.S. Application No. 09/542,473; Filed: April 4, 2000; Takayuki IKEDA et al.; ELECTROOPTICAL DEVICE AND A METHOD OF MANUFACTURING THE SAME	
		H. FURUE et al., P-78: Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLCD Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability; SID 98 Digest, pgs. 782-785.	
		T. YOSHIDA et al., 33.2: A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time, SID 97 Digest, pgs. 841-844.	
The		M. LEE et al., New Polycrystalline Silicon TFT's with Selectively Doped Region in The Channel, IDW '99 Proceedings of The Sixth International Display Workshops, December 1-3, 1999, pgs. 1097-1098.	
. •			

^{*} EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

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3			U.S. PATENT DOCU	MENTS				
*	Cite:	U.S. From Document	Publication Data	Name of Patente	s Cer	Pages, Columns, Lines, Wh	ere Re	
/		Number - Kind Code ((f Impun)	NOTOP 1777	Applicant of Ched D	ocument.	Persones or Relevant Figu	nes Ap	
∀.		716.4.094.022	01-08-1991	ISHIZU et al.				
W_		US-4,984,033 US-5,341,012	08-23-1994	MISAWA et al				
			10-06-1998	SATO				
100000	US-5,818,552 US-5,998,838 US-6,066,860 US-6,278,131 B1 / US-2001/0029070 A1		12-07-1999	TANABE et al				
			05-23-2000		KATAYAMA et al.			
			08-21-2001	YAMAZAKI et al.				
			10-11-2001	YAMAZAKI	YAMAZAKI et al.			
		US-6,316,787 B1	11-13-2001	OHTANI				
		:US-6,330,044 B1	12-11-2001	MURADE				
		US-6,590,229 B1	07-08-2003	YAMAZAKI	t al.			
		US-6,639,244 B1	10-28-2003	YAMAZAKI	tal.			
< n		US-2004/0056296 A1	03-25-2004	ARAO et al.				
X	100000	US-2004/0065882 A1	04-08-2004	YAMAZAKI	t al.			
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'Applicant's unique citation designation number (optional). 'See Kinds Codes of USPTO Petent Documents at 222 uspto.gov or MPEP 901.04. 'I Enter Office that issued the document, by the two-letter code (WIPO Standard STJ). 'For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 'Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possibile.' 'Applicant is to place a check mark here if English language Translation is attached.

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				Examiner Name			G. Ec	kert, II			
Sheet	Sheet of 2			Attorney Docket Nui	nber		74075	6-2626			
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milats				Publication Date NO4-DD-YYYYY		Name of Pate Applicant of Cool		Relevant Passagus or 8	do no		
		- tolunia - state francis (A sistant						Figures Appear			
1		US-5,182,620	01/	1993	Shimada et	al.					
10/		US-5,739,549	04/	1998		Takemura et al. Moon					
W /		US-5,942,310	08/	1999							
1/		US-6,067,132	05/	2000	Kim Jeong Yamazaki et al.						
1		US-6,137,551	10/	2000							
		US-6,271,818	08/	2001				\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \			
L		US-6,490,014	12/	2002		Ohtani et al					
			: ::::::								
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. No.											
IXI_		GB 2-307 326		05/1997		Shin et al.					
					+				100000		
				RT – NON PATENT I							
Examiner Initials	Cite No.1	Include name of the item (book, magazi	c author ne, jour	(in CAPITAL LETTE nal, serial, symposium, publisher, city and/or	catalog.	etc. L. date: page(x):	volume es	te j, title of the sise mimber(s),	7		
We	Shimokawa et al., "Character MBIC Measurement", Japane pp. 751-758.		erization of High nese Journal of A	-Effic Applied	iency Cast-Si I Physics, Vo	Solar C 1, 27, N	cell Wafers by o. 5, May, 1988,				

	THE A REPORT	PPA . Bufatat		، المفد الالمسامات			Ann formance	with MPFP	600 Denvil	ne through citati	on if not in co	nformance and not
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Applicant's unique citation designation number (optional). *See Kinds Codes of USPTO Patent Documents at https://www.uspio.gov/cr/mPEP-901.04. *Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). *For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. *Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. *Applicant is to place a check mark here if English language Translation is attached.

¹ Applicant's unique citation designation number (options). Applicant is to place a check mark here if English language Translation is attached.

Form PTO-1449 U.S. Departs (Rev. 8-83) Patent and		of Commerce lemark Office	Attorney Docker: 740	J/30-2626	Serial No.	
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			Filing Date: June 26	, 2003	Group: 2815	
•			OCUMENTS Name	Class	Subclass	Filing
xaminer	Document Number	Date	Name	Class	Suociass	Date
nijal	C C42 90C	07/01/1997	Ohtani et al.			Date
W	5,643,826	07/13/1999	Ohtani et al.			- 1
	5,923,962 5,895,933	04/20/1999	Zhang et al.	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \		\\
	5,882,960	03/16/1999	Zhang et al.	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \		\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
	5,608,251	03/04/1997	Konuma et al.	/	/	`
	5,620,905	04/15/1997	Konuma et al.			/
	5,712,495	01/27/1998	Suzawa	65 1060 MAG		1
	5,856,689	01/05/1999	Suzawa			
	5,998,841	12/07/1999	Suzawa		/	
	4,409,724	10/18/1983	Tasch et al.		/	
	4,823,180	04/18/1989	Wieder et al.	/)
	4,851,370	07/25/1989	Doklan et al.			····(···
	4,886,962	12/12/1989	Gofuku et al.)
	5,292,675	03/08/1994	Codama			
	5,343,066	08/30/1994	Okamoto et al.			\\
	5,365,079	11/15/1994	Kodaira et al.			
	5,616,935	:04/01/1997	Koyama et al.		7	
VMC	5,508,209	04/16/1996	Zhang et al.			1000000000
			T DOCUMENTS			
	Document Number	Date	Country	Class	Subclass	Translati
+1/2	07-130652	05/19/1995	Japan		T. V	Abstrac
	07-321339	12/08/1995	Japan		\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	Abstrac
	09-312260	12/02/1997	Japan		(Abstrac
	10-056184	02/24/1998	Japan			Abstrac
	10-247735	09/14/1998	Japan	S		Abstrac
	07-130974	05/19/1995	Japan			Abstrac
	07-135323	05/23/1995	Japan			Abstrac
	07-169974	.07/04/1995	Japan			Abstrac
\ 1,	07-169975	070/4/1995	Japan	· · · · · · · · · · · · · · · · · · ·		Abstrac
Dev	07-212932	08/18/1995	Japan			Abstrac
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